: IDS filed 9/23/03 (5 pages ATTY. DOCKET NO. SERIAL NO. FORM PTO-1449 (Modified) Unassigned 10/66760 FIS920030186US1 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT: APPLICANT'S INFORMATION DISCLOSURE Dureseti Chidambarrao, et al. **STATEMENT** 9/23/2003 FILING DATE: GROUP: (Use several sheets if necessary) Concurrently Herewith Unassigned. REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT **FILING DATE** NUMBER **CLASS** INITIALS DATE NAME **SUBCLASS** (IF APPRO.) 6,228,694 B1 5/8/2001 Doyle et al. 6,406,973 B1 6/18/2002 Lee 6,281,532 B1 8/28/2001 Doyle et al. 5,683,934 11/4/97 Candelaria 6,368,931 B1 4/9/2002 Kuhn, et al. 5,310,446 5/10/94 Konishi et al. 4,853,076 8/1/89 Tsaur et al. US 2002/0090791 A1 7/11/2002 Doyle et al. US 2002/0074598 A1 6/20/2002 Doyle et al. 6,509,618 B2 7/21/2003 Jan et al. 6,476,462 B2 11/5/2002 Shimizu et al. 6,362,082 B1 3/26/2002 Doyle et al. 6,228,694 B1 5/8/2001 Doyle et al. 5,565,697 10/15/96 Asakawa et al. US 2003/0040158 A1 2/27/2003 Saitoh US 2002/0086472 A1 7/4/2002 Roberds et al. 6,521,964 B1 2/18/2003 Jan et al. 6,506,652 01/14/03 Jan, et al. FOREIGN PATENT DOCUMENTS DOCUMENT TRANSLATION NUMBER DATE COUNTRY SUBCLASS CLASS YES NO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) M. Kennedy Considered EXAMINER/ EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if

not in conformance and not considered. Include copy of this form with next communication to applicant.

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bu	6,501,121	12/31/2002	Yu, et al.					
Sal	6,498,358	12/24/2002	Lach, et al.					
On	6,493,497	12/10/2002	Ramdani, et al.					
10	6,403,975	6/11/2002	Brunner, et al.		1/			
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MI	6,246,095	6/12/2001	Brady, et al.	7				
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au	6,261,964	7/17/2001	Wu, et al.				-		
M	6,221,735	4/24/2001	Manley, et al.			/			
Me	6,117,722	9/12/2000	Wuu, et al.			/			
ON	6,107,143	8/22/2000	Park, et al.						
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ge	5,840,593	11/24/1998	Leedy						
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que	Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress", International Electron Devices Meeting, 34.4.1, IEEE, September 1999							
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